

<b>Notice of References Cited</b>	Application/Control No. 10/773,315		Applicant(s)/Patent Under Reexamination KURODA ET AL.	
	Examiner Hai L. Nguyen		Art Unit 2816	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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X	C	US-6,081,462	06-2000	Lee, Terry R.	365/194
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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